Abstracts

On-Wafer Characterization of Monolithic Millimeter-Wave Integrated Circuits by a Picosecond Optical Electronic Technique

P. Polak-Dingels, H.-L.A. Hung, T. Smith, H.C. Huang, K.J. Webb and C.H. Lee. "On-Wafer Characterization of Monolithic Millimeter-Wave Integrated Circuits by a Picosecond Optical Electronic Technique." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 237-240.

A new picosecond optical electronic sampling technique for the characterization of monolithic microwave integrated circuits (MMICs) has been developed. The measured time domain response allows the spectral transfer function of the MMIC to be obtained. This technique was applied to characterize the frequency response of a two-stage Ka-band MMIC amplifier. The broadband results agree well with those obtained by conventional network analyzer measurements.

❑ Return to main document.